

## Special Issue

# Ultrasonic and Electromagnetic Waves for Nondestructive Testing

### Message from the Guest Editors

This Special Issue welcomes theoretical and practical contributions aimed at further understanding ultrasonic and electromagnetic nondestructive testing technologies, including (but not limited to) high-resolution detection, multidimensional imaging, image processing, and data fusion. In addition, it also seeks reports on quality assessment in specific application scenarios with ultrasonic and electromagnetic nondestructive testing technologies.

- ultrasonic testing
- microwave detection
- terahertz imaging
- infrared testing
- defect detection and evaluation
- in-situ detection
- intelligent recognition

We look forward to receiving your contributions.

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### Guest Editors

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### Deadline for manuscript submissions

15 November 2025



## Electronics

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## About the Journal

### Message from the Editor-in-Chief

*Electronics* is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guestedited by leading experts in selected topics of interest.

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### Editor-in-Chief

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